

**University of New Mexico**  
Department of Electrical and Computer Engineering

**ECE 321 – Electronics I (Fall 2009)**

**Exam 4**

Name: ~~Solution~~ Solutions

Date: Dec. 9, 2009

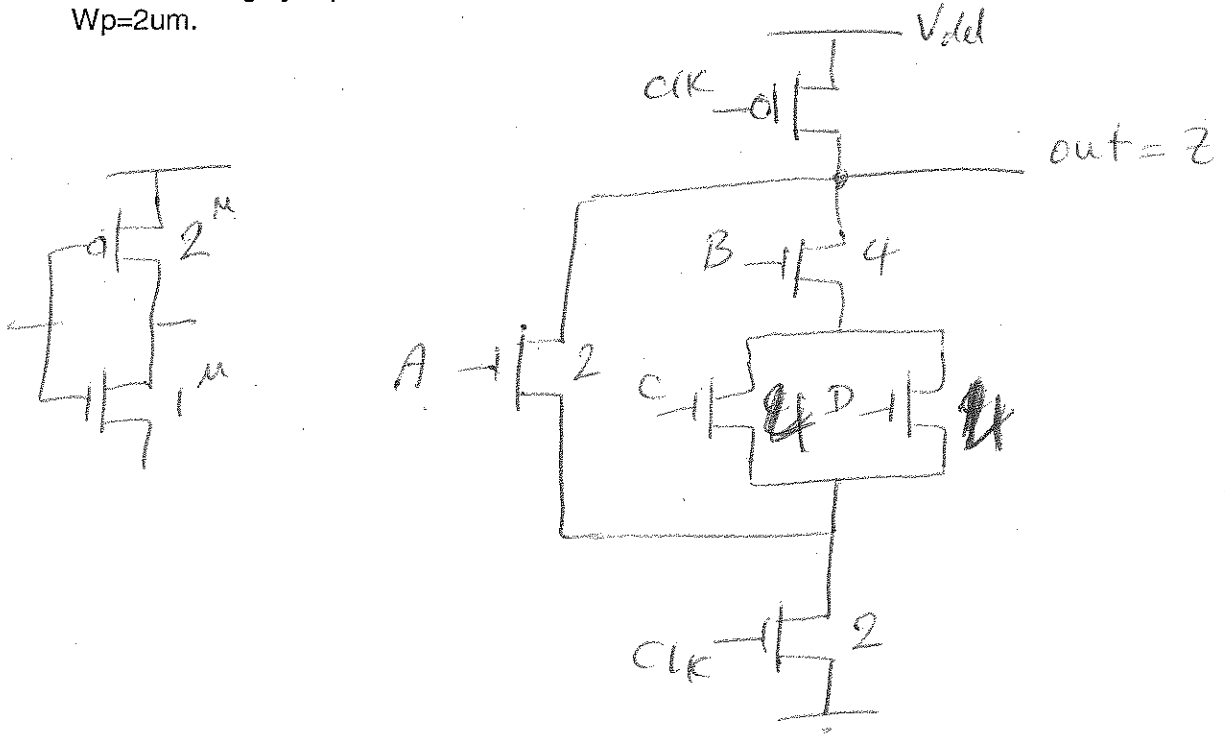
Note: Only calculator, pencils, and pens are allowed.

1. (10 points) Fill in the blank:

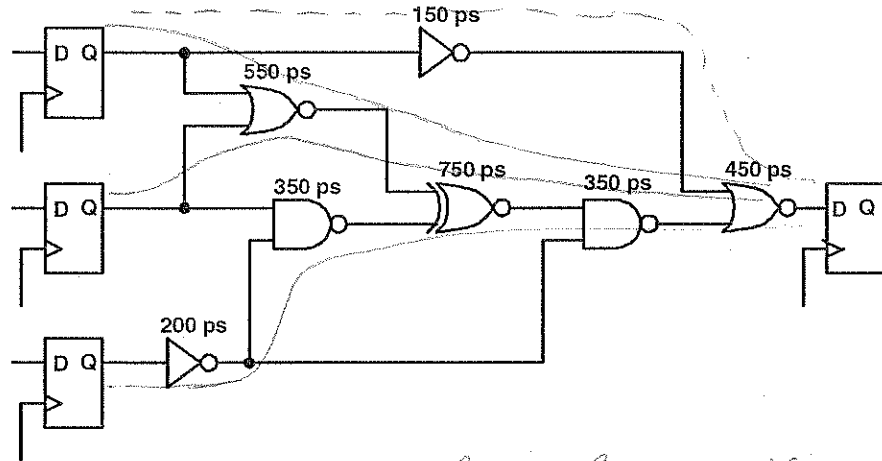
- (a) In a flip-flop, the time that the input data needs to be stable after the rising edge of the clock is called hold time.
- (b) Contamination delay is Minimum delay.
- (c) An 8-input dynamic logic NAND gate requires 10 transistors.
- (d) NMOS is good in passing 0 and PMOS is good in passing 1.
- (e) If the average propagation delay of an inverter is 100ps, then a ring oscillator of 21 stages of inverter will oscillate at the frequency of 238 MHz.

2. (20 points) Dynamic logic design problem:

- (a) Draw the circuit diagram of a dynamic logic that performs  $Z = A + B(C + D)$ .
- (b) Determine the width of NMOS transistors, such that the worst case  $t_{pHL}$  delay becomes roughly equivalent to a referenced inverter with  $W_n=1\mu m$  and  $W_p=2\mu m$ .



3. (30 points) Consider the following sequential circuit with 4 edge-triggered flip-flops and some logic gates. Assume that  $t_{SU} = 3 \text{ ns}$ ,  $t_{hold} = 2 \text{ ns}$ , and  $t_{C2Q} = 1 \text{ ns}$ .
- Identify the path with the maximum delay (critical path) on the schematic.
  - What is the maximum operating frequency of this circuit?
  - Identify the path with minimum delay on the schematic.
  - Does this circuit violate the hold time constraint? Why?



a)  $t_{logic \max} = 550 \text{ ps} + 750 \text{ ps} + 350 \text{ ps} + 450 \text{ ps} = 2.1 \text{ ns}$

b)  $T \geq 1 \text{ ns} + 2.1 \text{ ns} + 3 \text{ ns} = 6.1 \text{ ns} \Rightarrow f = 164 \text{ MHz}$

c)  $t_{logic \min} = 150 \text{ ps} + 450 \text{ ps} = 600 \text{ ps}$

d)  $t_{hold} < t_{cq} + t_{logic \min} \Rightarrow 2 \text{ ns} < 1 \text{ ns} + 0.6 \text{ ns} = 1.6 \text{ ns}$

no  
Violation

4. (40 points) The following circuit is a 4-input dynamic logic.
- Identify the logic function for the output Z.
  - What input vector imposes the worst case charge sharing during the evaluation time?
  - Compute the final voltage at Z, if the input vector is ABCDE=11000 during evaluation after charge sharing. Assume that  $V_{tn} = 0.4V$ .
  - Determine the width of the PMOS such that the maximum worst case pre-charge time delay (0 to 90%) is limited to 250ps. (The worst case is when all the inputs are at  $V_{DD}$  such that all the intermediate capacitors contribute to the delay). Assume that  $V_{DD} = 1.2V$ ,  $K'_p = 50 \mu A/V^2$ , and  $V_{tp} = -0.5V$  in the 100nm technology node. For simplicity assume that the PMOS will stay in saturation during the transition.

a)  $Z = \overline{A(B+C+D+E)}$

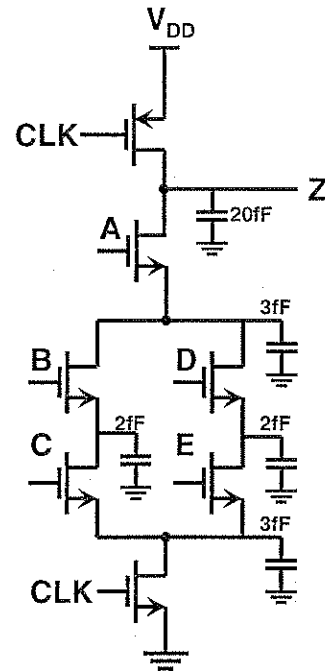
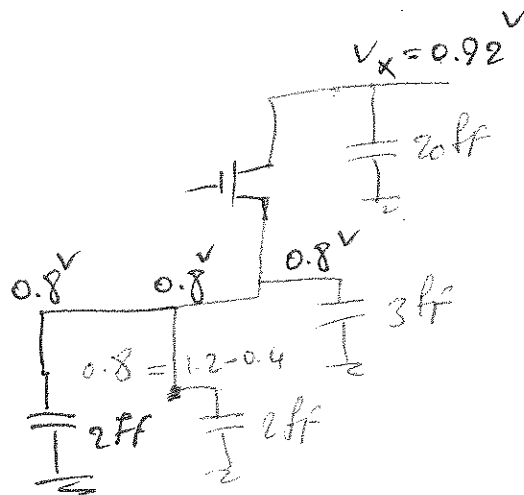
b) ABCDE = 11010

c)

$$1.2V + 20pF = 20pF + V_f$$

$$+ \frac{1pF}{7} \times 0.8$$

$$\Rightarrow V_f = 0.92V$$



d)

$$t_d = \frac{C \cdot \Delta V}{I_a} \Rightarrow$$

$$250ps = \frac{30pF \cdot (0.9 + 1.2)}{\frac{50 \mu A/V^2}{2} + \left(\frac{W}{L}\right)_p (1.2 - 0.5)^2}$$

$$\frac{K'_p}{2} \left(\frac{W}{L}\right)_p (V_{DD} - V_{tp})^2$$

$$\Rightarrow \left(\frac{W}{L}\right)_p = 10.58$$

$$\Rightarrow W_p = 1.058 \mu m$$

5. (10 bonus points) The following are bonus questions:
- (a) In problem 3, how do you modify the circuit to avoid the hold time violation without any penalty on the operating frequency? (5 bonus credit)
  - (b) Leakage current is another problem for dynamic logics. If  $I_{off}$  is 100pA for each NMOS in problem 4, which input vectors give the maximum leakage? How much is the maximum leakage? (5 bonus credit)

a) add 4 inverters to the minimum path.

b)

ABCDE = 11010  
10110  
11001  
10010